

FDMS8018

December 2015

D

N-Channel PowerTrench[®] MOSFET 30 V, 175 A, 1.8 m Ω

Features

- Max $r_{DS(on)} = 1.8 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 30 \text{ A}$
- Max $r_{DS(on)} = 2.4 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 26 \text{ A}$
- Advanced Package and Silicon Combination for Low r_{DS(on)} and High Efficiency
- Next Generation Enhanced Body Diode Technology, Engineered for Soft Recovery
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

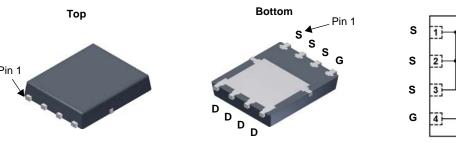


General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency and to minimize switch node ringing of DC/DC converters using either synchronous or conventional switching PWM controllers.It has been optimized for low gate charge, low $r_{\rm DS(on)}$, fast switching speed ang body diode reverse recovery performance.

Applications

- VRM Vcore Switching for Desktop and Server
- OringFET / Load Switching
- DC-DC Conversion
- Motor Bridge Switch



Power 56

MOSFET Maximum Ratings $T_A = 25$ °C unless otherwise noted

Symbol	Paramet	ter		Ratings	Units
V_{DS}	Drain to Source Voltage			30	V
V_{GS}	Gate to Source Voltage		(Note 4)	±20	V
	Drain Current -Continuous	T _C = 25 °C	(Note 6)	175	
	-Continuous	T _C = 100 °C	(Note 6)	110	Α
ID	-Continuous	T _A = 25 °C	(Note 1a)	30	^
	-Pulsed		(Note 5)	680	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	126	mJ
D.	Power Dissipation	$T_C = 25 ^{\circ}C$		83	w
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1a)	2.5	VV
T_J , T_{STG}	Operating and Storage Junction Temperate	ure Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8018	FDMS8018	Power 56	13 "	12 mm	3000 units

Units

Max

Electrical Characteristics T_J = 25 °C unless otherwise noted

Parameter

Off Characteristics								
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V		
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25 °C		14		mV/°C		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ		
I _{GSS}	Gate to Source Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA		

Test Conditions

Min

Тур

On Characteristics

Symbol

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	1.5	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-6		mV/°C
		V _{GS} = 10 V, I _D = 30 A		1.5	1.8	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 26 \text{ A}$		1.9	2.4	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 125 \text{ °C}$		2.2	2.7	
9 _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 30 A		194		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45 V V 0 V	3935	5235	pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	1380	1835	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1011 12	137	210	pF
R_q	Gate Resistance		0.9		Ω

Switching Characteristics

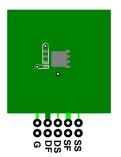
t _{d(on)}	Turn-On Delay Time		15	27	ns
t _r	Rise Time	V _{DD} = 15 V, I _D = 30 A,	7.3	15	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	38	62	ns
t _f	Fall Time		4.8	10	ns
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V	58	61	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 15 \text{ V}$	28	39	nC
Q _{gs}	Gate to Source Charge	I _D = 30 A	10.3		nC
Q _{gd}	Gate to Drain "Miller" Charge		7.7		nC

Drain-Source Diode Characteristics

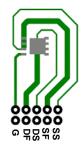
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A}$ (Note 2))	0.67	1.1	\/
	Source to Drain blode Forward voltage	$V_{GS} = 0 \text{ V}, I_{S} = 30 \text{ A}$ (Note 2)	0.77	1.2	V
t _{rr}	Reverse Recovery Time	1 20 A di/dt 100 A/v.a		43	69	ns
Q _{rr}	Reverse Recovery Charge	$I_F = 30 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		25	40	nC
t _{rr}	Reverse Recovery Time	1 20 A di/dt 200 A/ a		34	55	ns
Q _{rr}	Reverse Recovery Charge	$I_F = 30 \text{ A}, \text{ di/dt} = 300 \text{ A/}\mu\text{s}$		46	72	nC

Notes:

1. R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a) 50 °C/W when mounted on a 1 in² pad of 2 oz copper



b) 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 $\mu\text{s},$ Duty cycle < 2.0%.
- 3. Starting T $_{J}$ = 25 °C; N-ch: L = 0.3 mH, I $_{AS}$ = 29 A, V $_{DD}$ = 27 V, V $_{GS}$ = 10 V.
- 4. As an N-ch device, the negative Vgs rating is for low duty cycle pulse occurrence only. No continuous rating is implied.
- 5. Pulsed Id please refer to Fig 11 SOA graph for more details.
- 6. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

Typical Characteristics T_J = 25 °C unless otherwise noted

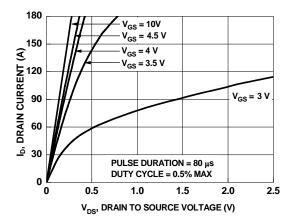


Figure 1. On Region Characteristics

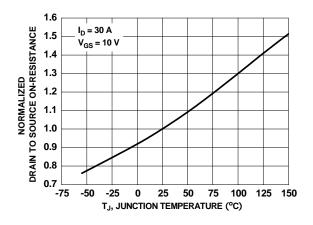


Figure 3. Normalized On Resistance vs Junction Temperature

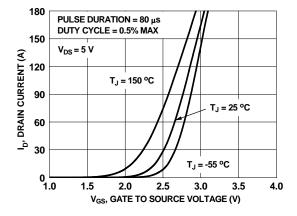


Figure 5. Transfer Characteristics

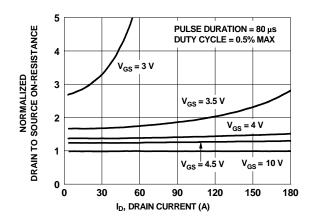


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

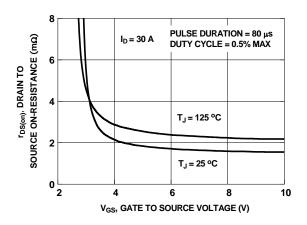


Figure 4. On-Resistance vs Gate to Source Voltage

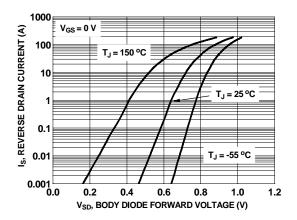


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

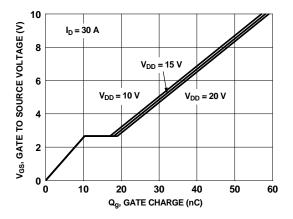


Figure 7. Gate Charge Characteristics

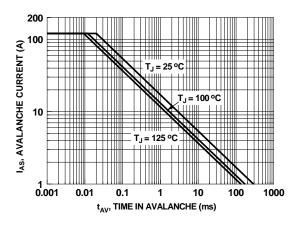


Figure 9. Unclamped Inductive Switching Capability

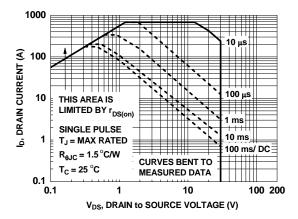


Figure 11. Forward Bias Safe Operating Area

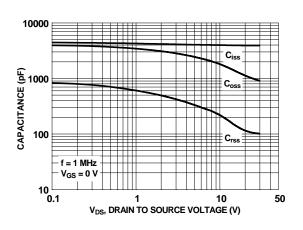


Figure 8. Capacitance vs Drain to Source Voltage

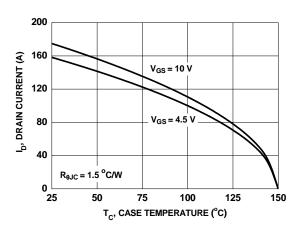


Figure 10. Maximum Continuous Drain Current vs Case Temperature

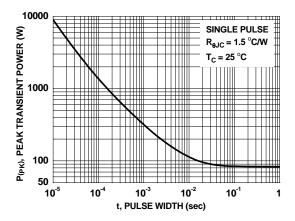


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

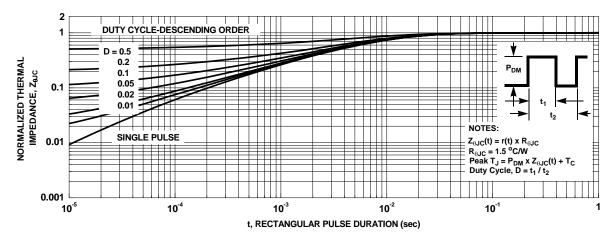
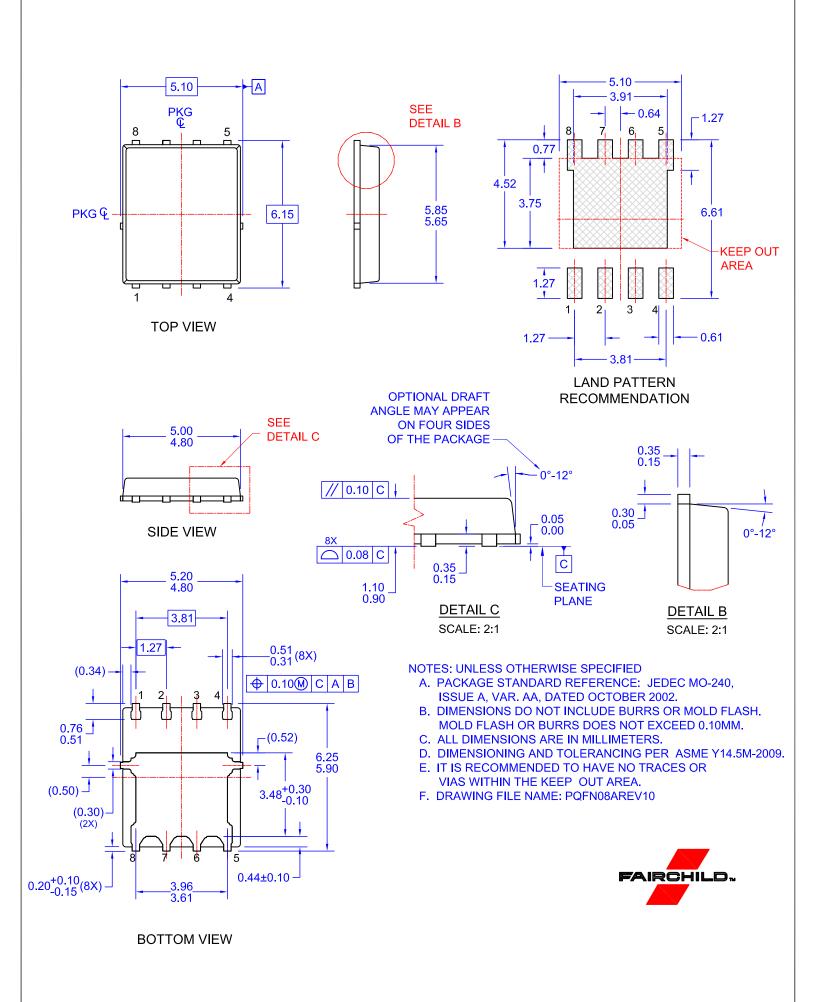


Figure 13. Junction-to-Ambient Transient Thermal Response Curve



ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdt/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative